

INTERNATIONAL SEARCH REPORT

International Application No

PCT/G5 03/04429

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01R31/26

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC 7 G01R

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

INSPEC, EPO-Internal

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	PLATZKER A ET AL: "Characterization of GaAs devices by a versatile pulsed I-V measurement system" MICROWAVE SYMPOSIUM DIGEST, 8 May 1990 (1990-05-08), pages 1137-1140, XP010004518	1-4,6, 11,14-17
Y	*The whole document*	5
X	EP 0 800 091 A (MITSUBISHI ELECTRIC CORP) 8 October 1997 (1997-10-08)	1,3,14, 15
Y	column 2, line 19 - column 3 line 10; column 19, line 53 -column 21, line 45; figures 22,27	5
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☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

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- *A* document defining the general state of the art which is not considered to be of particular relevance
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- *O* document referring to an oral disclosure, use, exhibition or other means
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- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
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- * & * document member of the same patent family

Date of the actual completion of the international search

8 March 2004

Date of mailing of the international search report

17/03/2004

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	FUJII K: "An improved GaAs MESFET model for the pulsed I-V measurement" MICROWAVE SYMPOSIUM DIGEST, 1995., IEEE MTT-S INTERNATIONAL ORLANDO, FL, USA 16-20 MAY 1995, NEW YORK, NY, USA, IEEE, US, 16 May 1995 (1995-05-16), pages 615-618, XP010612290 ISBN: 0-7803-2581-8	1, 14
A	*The whole document*	2-13, 15-18
X	----- BARTON T M: "NARROW PULSE MEASUREMENT OF DRAIN CHARACTERISTICS OF GAAS MESFETS" ELECTRONICS LETTERS, IEE STEVENAGE, GB, vol. 23, no. 13, 18 June 1987 (1987-06-18), pages 686-687, XP002057571 ISSN: 0013-5194 *The whole document* -----	1, 2, 14

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Form PCT/ISA/210 (patent family annex) (July 1992)